	·		
	Application No.	Applicant(s)	and on the same of
Nation of Allowahility	10/754,417	TASHIRO ET AL.	
Notice of Allowability	Examiner	Art Unit	
	James A. Dudek	2871	
All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT R of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in or other appropriate commu IGHTS. This application is s	this application. If not include inication will be mailed in due	ded course. THIS
1. X This communication is responsive to the RCE filed 6/17/05	<u>5</u> .		
2. ☑ The allowed claim(s) is/are <u>9-13</u> .			
3. $igotimes$ The drawings filed on $\underline{\it 09 January 2004}$ are accepted by th	e Examiner.		
4. Acknowledgment is made of a claim for foreign priority una All b) Some* C None Of the: 1. Certified copies of the priority documents have Certified copies of the certified copies of the priority documents have Certified copies not received: **Certified copies not received: Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 5. A SUBSTITUTE OATH OR DECLARATION must be subminformal PATENT APPLICATION (PTO-152) which give CORRECTED DRAWINGS (as "replacement sheets") must (a) including changes required by the Notice of Draftspers 1) hereto or 2) to Paper No./Mail Date (b) including changes required by the attached Examiner' Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in the composition of the deposition of	e been received. e been received in Application ocuments have been received of this communication to file MENT of this application. Initted. Note the attached EXA es reason(s) why the oath or set be submitted. Son's Patent Drawing Review of Amendment / Comment or .84(c)) should be written on the header according to 37 CFI seit of BIOLOGICAL MATE	n No. 10/316,659. If in this national stage application this national stage application a reply complying with the result. MINER'S AMENDMENT or It declaration is deficient. (PTO-948) attached in the Office action of the drawings in the front (not the R 1.121(d).	equirements NOTICE OF
Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☑ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. ☐ Interview Su Paper No./I 08), 7. ☑ Examiner's /	formal Patent Application (PT Immary (PTO-413), Mail Date Amendment/Comment Statement of Reasons for All	·
		James A. Dudek Primary Examiner Art Unit: 2871	

EXAMINER'S AMENDMENT

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

The application has been amended as follows: claims 7-8 have been canceled.

The following is an examiner's statement of reasons for allowance: the prior art of record (for example US 20040180149A1) teaches a liquid crystal display device, comprising: a liquid crystal layer having any of positive or negative dielectric anisotropy provided between said first and second substrates [see paragraph 169]; and a polarizer disposed at an outer side of said first substrate [see 110 of figure 1], an optical phase compensation film disposed between said first substrate and said polarizer, said optical phase compensation film having a retardation $df[(n_x+n_y)/2 - n_z]$ so as to satisfy the relationship

$$0.4 \leq [df[(n_x + n_y)/2 \text{ -} n_z]]/(dlc \; \Delta n) \leq 0.7,$$

wherein n_x , n_y and n_z are refractive indices of said optical phase compensation film respectively in an x-direction, a y-direction and a z-direction, dlc is the thickness of said liquid crystal layer, and Δn is a refractive index difference between an extraordinary ray and an ordinary ray in the liquid crystal layer [see paragraph 0056-0057 1/Rt is equal to or less than 0.8333].

although not taught by 149, a first substrate [see paragraph 007]; a second substrate disposed so as to face said first substrate, said second substrate carrying projections and depressions having a reflectivity were well known for reducing power consumption.

The prior art of record does not teach nor suggest "said optical phase compensation film having a negative dielectric anisotropy in a direction perpendicular to a plane of said first substrate" [emphasis added.]

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue

Application/Control Number: 10/754,417

Art Unit: 2871

fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to James A. Dudek whose telephone number is 571-272-2290. The examiner can normally be reached on 9:00-5:30.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Robert H. Kim can be reached on 571-272-2293. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

James A. Dudek Primary Examiner Art Unit 2871